



Note, that all the above-mentioned wave-front sources  $C$  and  $C'$  and also the sources of reference and object waves are aligned on the optical axis of telescope mirrors unit when recording of HS. By taking into account this fact, the wave phase distribution for the ray beam spreading from the point source  $C$  on the PM surface can be described correct to a constant by the following expression which is written in the third-order approximation<sup>4</sup>:

$$v_C = \frac{2p}{l_c} \left\{ \frac{1}{2Z_C} \left( 1 - \frac{Z_C}{r_1} \right) X_1^2 - \frac{1}{8} \left( \frac{1}{Z_C^3} - \frac{2}{r_1 Z_C^2} + \frac{e_1}{r_1^3} \right) X_1^4 \right\}, \quad (5)$$

where  $Z_C$  is the distance from the point of  $C$  to a vertex of the secondary mirror along the  $Z$  axis, moreover, if the point is placed on the right of the mirror vertex, then  $Z_C > 0$ , if it is placed on the left, then  $Z_C < 0$ . Here  $r_1$  is the vertex radius of curvature of PM surface; the sign of  $r_1$  is determined by the sign of coordinate  $Z$  of the corresponding mirror curvature center;  $e_1$  is the function of eccentricity, it is determined from the equation describing the mirror surface shape as  $2rZ = X^2 + eZ^2$ . The vertex radius of curvature and eccentricity function of the secondary mirror are characterized further by the parameters  $r_2$  and  $e_2$ , respectively.

Let us write down analogous expressions for  $v_o$  and  $v_r$  and substitute them into Eq. (4), then

$$DW = -\frac{2p}{l_c} \left\{ \left[ \frac{1}{Z_C} - \frac{1}{r_1} + \frac{m}{2} \left( \frac{1}{Z_o} - \frac{1}{Z_r} \right) \right] X_1^2 - \frac{X_1}{8} \left[ \frac{2}{Z_C^3} - \frac{4}{r_1 Z_C^2} + \frac{2e_1}{r_1^3} + m \left( \frac{1}{Z_o^3} - \frac{1}{Z_r^3} - \frac{2}{r_1} \left( \frac{1}{Z_o^2} - \frac{1}{Z_r^2} \right) \right) \right] \right\} - 2D v_{2-1}. \quad (6)$$

Having equalled the coefficient for  $X_1^2$  to zero we obtain from Eq. (6) the condition of autocollimation reflection from the mirror  $1$  with the hologram structure of the ray beam diverging from the point  $C$ :

$$\frac{1}{Z_C} - \frac{1}{r_1} + \frac{m}{2} \left( \frac{1}{Z_o} - \frac{1}{Z_r} \right) = 0. \quad (7)$$

If condition (7) is valid Eq. (6) describing the wave front aberration of the third order in the interferometer  $\bar{5}$  is reduced to the form

$$DW = -\frac{2p}{l_c} \frac{X_1^4}{8} \left[ \frac{2}{Z_C^3} - \frac{4}{r_1 Z_C^2} + \frac{2e_1}{r_1^3} + m \left( \frac{1}{Z_o^3} - \frac{2}{r_1 Z_o^2} - \frac{1}{Z_r^3} + \frac{2}{r_1 Z_r^2} \right) \right] - 2D v_{2-1}; \quad (8)$$

where, taking Eq. (4) into account

$$D v_{2-1} = \frac{2p}{l_c} S_{2-1} X_1^4,$$

$$S_{2-1} = \frac{Z_C^4}{Z_C^4} \frac{1}{4r_2} \left( \frac{1}{Z_C^2} - \frac{2}{r_2 Z_C} + \frac{e_2}{r_2^2} \right). \quad (9)$$

By substituting Eq. (9) into Eq. (8) we obtain the following expression under autocollimation condition (7)

$$DW \sim \frac{2p}{l_c} \frac{X_1^4}{8} \left\{ \frac{6}{Z_r^2} \left( \frac{1}{r_1} - \frac{1}{Z_C} \right) + \frac{4}{Z_r} \left( \frac{1}{r_1} - \frac{1}{Z_C} \right) \times \left( \frac{3}{mr_1} - \frac{3}{mZ_C} - \frac{2}{r_1} \right) + \frac{8}{m^2} \left( \frac{1}{r_1} - \frac{1}{Z_C} \right)^3 - \frac{8}{mr_1} \left( \frac{1}{r_1} - \frac{1}{Z_C} \right)^2 + \frac{1}{Z_C^3} - \frac{4}{r_1 Z_C^2} + \frac{2e_1}{r_1^3} - 16 S_{2-1} \right\}. \quad (10)$$

At specified values of  $Z_C$  and  $DW$  the Eqs. (7) and (10) make it possible to determine such wavelengths of the HS recording and reconstruction as well as such distances from the PM vertex up to the reference and object sources at which the autocollimation path of rays will be realized for preset aberrations (for example, for zero aberrations) in the telescope control channel. Because the values of  $Z_C$ ,  $DW$ , and  $S_{2-1}$  are given, as a rule, and the parameters  $Z_o$  and  $Z_r$  are generally related between each other by the autocollimation condition then as it follows from Eq. (10), there is the only one free parameter  $m$  by means of which the values of  $Z_o$  and  $Z_r$  can be influenced when recording of HS.

Let us consider an effect of the parameter  $m$  and, consequently, the wavelength of PM shape control on  $Z_o$  and  $Z_r$  more attentively. For that let the point  $C$  (as it was proposed in Ref. 1) be in the focal plane of PM, i.e.,  $Z_C = r_1/2$  and the notations  $Z_r = R r_1$  and  $Z_o = O r_1$  be introduced. Then from Eqs. (7) and (10) we obtain

$$\frac{1}{R} = \frac{2}{3} + \frac{1}{m} + \frac{0.58}{m} \sqrt{B}, \quad (11)$$

$$\frac{1}{O} = \frac{2}{3} - \frac{1}{m} + \frac{0.58}{m} \sqrt{B}, \quad (12)$$

$$B = -m^3 r_1^3 \frac{4l_o}{2p X_1^4} DW + m^2 \left( e_1 - 8 r_1^3 S_{2-1} + \frac{4}{3} \right) - 1.$$

Note, that only the positive values of parameters  $R$  and  $O$  are of interest for experience, i.e., it is the case when recording of the hologram structure is carried out by the ray beams diverging from the reference and object sources located on the same side of the primary mirror. For the general case when  $e_1$ ,  $S_{2-1}$  are small and  $DW = 0$ , the above-indicated relation is satisfied for the sign "+" before the radical and for  $m > 1$ . In this case the parameter  $R$  is virtually independent of  $m$  and the parameter  $O$  decreases essentially when  $m$  increases. This behavior is illustrated by the curves for  $R$  and  $O$  as functions of  $m$  which are presented in Fig. 2 and calculated for  $e_1 = S_{2-1} = DW = 0$ .

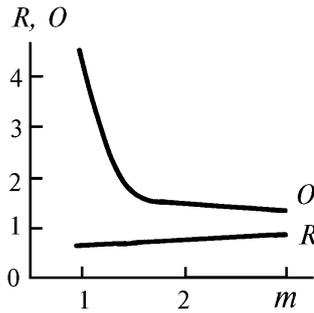


FIG. 2. Parameters  $R$  and  $O$  as functions of the ratio of the control channel operation wavelength to PM recording wavelength.

The results of analysis carried out make it possible to draw two main conclusions. First, recording of hologram structure on the primary mirror surface at the wavelength being more than operation one of telescope control channel is not possible. Second, it is reasonable to increase the used wavelengths ratio from the point of view of decreasing in the required overall dimensions of recording setup of the holographic structure as well as increasing in the used wavelength ratio. Thus two-fold increasing in the wavelength allows us to reduce a length of the holographic structure recording setup more than by the factor of four, as it follows from Fig. 2. Note, that transition to a greater wavelength, naturally, must not cause a loss in the accuracy of PM shape control. It requires, in its turn, special care to be taken to keep a constant value of minimum deformation  $dH_1$  of PM surface measured by WFS.

To keep a value of this parameter unchanged we use a simplified expression for the sensitivity of interferometric control of photodetector  $S_s$ . This relation is obtained by the known equation for the interference bandwidth  $H_l$  (Ref. 6) and definition of the limiting phase resolution  $s_{ph}$  (Ref. 7). Then the threshold sensitivity is characterized by the following relation:

$$H_l/dH_l = 2 p/s_{ph}, \quad H_l = l_c/2M \cos a, \quad (13)$$

where  $l_c$  is the wavelength in the control channel,  $a$  is the angle of incidence of ray on the PM surface at the given point,  $M$  is the number of reflections from PM, and  $H_l$  is the deviation of PM shape which corresponds to the change in optical path length difference by  $l_k$  for the given  $M$  and  $a$ .

In the considered variant of WFS:  $M = 1$ ,  $a = a(X)$ , where  $d/2 \ll X \ll D/2$ ,  $D$  is the diameter of PM, and  $d$  is the diameter of the hole in PM. The angle of incidence  $a$  is changeable here, so as autocollimation of the control beam is provided by HS rather than PM surface. In this case the expression for the sensitivity  $S_s$  has the form

$$S_s = \frac{4 p M \cos a}{s_{ph} l_c}, \quad (14)$$

Equation (14) includes the principle parameters the valid choice of which makes it possible to solve the problem on remaining unchanged the control accuracy allowing for the minimisation criterion for overall dimensions of PM recording scheme. The parameters in the numerator of Eq. (14) are determined by geometry of WFS and independent on the wavelength of radiation. The

denominator is an "invariant" relatively to the operation wavelength of control  $l_c$  when it is necessary to keep the constant parameter  $S_s$ . It means that the change in  $l_c$  requires the corresponding change in the parameter  $s_{ph}$ .

One of the factors restricting the limiting phase resolution  $s_{ph}$  is a value of potentially achievable accuracy of phase measurement  $s$  in the recording unit.

Let us evaluate the change in  $s$  when the control channel length  $l_c$  increases. The use of WFS on the basis of heterodyne interferometer provides forming of two beams of radiation with the frequencies  $f_1$  and  $f_2$  which differ in some fixed value of the difference frequency  $f_0$ . According to technical realization the high-stable value  $f_0$  cannot be too low and it is units or tens of kilohertz in the scheme of interferometer with acousto-optical modulator. That causes the necessity to use the dissector as an input element of recording unit of scanning photodetector of instantaneous operation.

To compare the energy efficiency of the operation wavelength of the control system, we consider a power model of measuring tract. The model includes the laser, AOFM, interferometer, PM with HS, and recording unit (see Fig. 1). As shown in Ref. 8, the value of potentially achievable accuracy of phase measurement  $s$ , limited by the shot component of the dark current of photodetector, is determined by the following relation:

$$s = (0.5 A \sqrt{I_d}) / (P K S \sqrt{t}), \quad (15)$$

where  $I_d$  is the dark current of photodetector,  $t$  is the measurement time,  $P$  is the light signal power,  $S$  is the photodetector sensitivity,  $K$  is the contrast of interference pattern,  $A$  is the parameter allowing for the laser noise.

The above relation describes the basic exchange relationships between the power of optical signal, measurement time and potentially achievable accuracy of phase-meter. It should be noted that this relation characterizes the recording unit only and does not take into account the sources of errors from other elements of WFS (PM, radiating source, and interferometer).

On the one hand, the change in the operation wavelength causes a change in the photocathode sensitivity  $S$  and, on the other hand, a change in the energy efficiency of optical tract  $h$ . In this case the power  $P$  at the photodetector input equals to  $P_1/h$ , where  $P_1$  is the laser radiation power. In its turn,  $h$  depends on energy transfer coefficient of individual optical elements included in the interferometer and HS. For example, when changing the wavelength from  $0.53 \mu\text{m}$  to  $1.06 \mu\text{m}$  the sensitivity of dissector photocathode is reduced by an order approximately,<sup>9</sup> while the requirement for an accuracy of phase measurement is doubled with doubling of wavelength as follows from Eq. (14). As is seen from Eq. (15), in this case to keep the constant measurement accuracy of PM deformations, the light signal power of the detector photocathode should be increased about 20-fold keeping the energy efficiency of the other components of WFS optical scheme unchanged.

In this connection we consider the principle requirements imposed on a laser source which would be used in WFS with PM. The power and wavelength of radiation, consumed electrical power, as well as the mass and overall dimension characteristics (they are especially important for orbital telescopes) can be placed into the category of such requirements. Moreover, the presence of hologram structure on the primary mirror of telescope results in unequal arms

of the WFS interferometer that leads to additional requirements imposed on the time coherence of a laser.

The He-Ne lasers having the high spatiotemporal coherence and stability of radiation frequency are customary to use in the control systems. However, application of He-Ne lasers to control the mirrors with HS is impossible due to lower radiation power for required weight and dimension characteristics. Moreover, the deficiency of power cannot be compensated by relatively short wavelength of radiation of these lasers.

As for powerful sources of short-wavelength radiation such as ion lasers on the inert gases (Ar, Kr), they cannot be used by reason of high power consumption that causes not only great power emission but, as a result, thermal and erosion distortions of gas-charge tubes. Apart from the exploitation difficulties that leads to the essential reduction in service lifetime of laser.

Allowing for all these facts from our point of view it is more reasonable to use the solid-state laser (SL) combining a possibility for obtaining high-powerful radiation with high efficiency and small dimensions of a source in the space telescope control system. The other essential advantage of SL is practically unlimited service time of an active element.

Of all the SL's the YAG:Nd laser is the most convenient radiating source. The following advantages of this laser should be noted: a possibility for obtaining the powerful coherent radiation with diffraction divergence as well as possibility for operating in the different regimes of lasing (CW, pulsed, and pulsed-periodic). Besides, let us especially note a possibility for creating the compact YAG:Nd lasers with extremely low consumed power and high efficiency in the case of using the laser diode or light diode pumping of an active element.

Successes have recently been achieved in the field of manufacturing methods of semiconductor structures lead to an appearance of high-efficiency compact YAG:Nd lasers with pumping by laser diodes and whose radiation powers are up to 1 kW at the principle wavelength 1.06  $\mu\text{m}$  in the regime of multimode lasing<sup>10</sup> and up to 15 W in the single-frequency regime.<sup>11</sup>

To obtain the short-wave radiation conventionally used for the interferometric control of mirror quality, it is necessary to double the radiation frequency of YAG:Nd laser ( $l = 0.53 \mu\text{m}$ ). However the frequency doubling leads to essential losses in the output power that testifies good prospects in the use of principle harmonic of YAG:Nd laser radiation in the WFS. To test validity of the exchange relations for the radiation wavelength 1.06  $\mu\text{m}$  we carried out the experiments on revealing the power potentialities of these lasers. We used YAG:Nd lasers with both the diode and lamp pumping allowing us to obtain the highest levels of radiation power.

To obtain radiation with the narrow spectral line and hence with the high time coherence that is important for producing the interferometers with nonzero path length difference in the operation and reference channels, a selection of longitudinal types of laser oscillations is required. Because the YAG:Nd laser is the laser with the homogeneously prolonged line of gain, the single-frequency lasing can be obtained by elimination of spatial inhomogeneity in the electromagnetic field in a resonator by means of creation of the running wave. Such a regime is much more easily implemented in the circular resonators with the Faraday optical shutter.<sup>12</sup> According to this principle the optical arrangements of studied laser resonators were constructed.

In the experiments on determination of the power potentialities of the YAG:Nd lasers with the lamp

pumping we used the single-frequency CW laser. The technical solutions developed in Refs. 13 and 14 are taken as the basis of construction of the above laser. An active element was YAG:Nd crystal of 4 mm diameter and 65 mm length. The active element was pumped by the arc krypton lamp of the DNP-4/60 type. The single-frequency lasing with the mean maximum radiation power 4.5 W for the electrical power of pumping 1.8 kW was obtained in the experiments. To compare let us note that the maximum power of single-frequency radiation of the second harmonic ( $l = 0.53 \mu\text{m}$ ) obtained in the analogous laser scheme is 200 mW (see Ref. 13). These results testify that exchange relations (14) and (15) are satisfied.

To study the power potentialities of the single-frequency YAG:Nd lasers with the semiconductor pumping, a scheme of the single-frequency monolithic ring laser so-called chip-laser with the longitudinal laser diode pumping of an active element was chosen.

The resonator of the chip-laser is formed by the prism active element in which the ray path is set by total internal reflection from the prism faces.<sup>15,16</sup> This sufficiently simplifies the laser construction and, besides, makes it stable to disadjustments. The other advantage of the considered resonator configuration is its compactness.

To pump the active element, the phototypes of GaAlAs-laser diodes with the radiating power 500 mW at the wavelength 807 nm were used in our experiments. The obtained maximum radiation power in the single-frequency regime was 80 mW at the wavelength 1.06  $\mu\text{m}$ . Note, the power level of the chip-laser can be sufficiently increased, for example, up to 15 W in the master-oscillator - amplifier scheme.<sup>11</sup> Hence, in the case of YAG:Nd laser with diode pumping the exchange relations are also satisfied.

The analysis carried out verifies the advisability and good prospects of using the YAG:Nd lasers in WFS of adaptive telescopes with the hologram structure on the primary mirror. In this case the choice of the principle harmonic of radiation of these lasers makes it possible not only to reduce the dimensions of setup for hologram structure recording keeping the absolute accuracy of control of mirror surface shape but to refuse from the frequency doubling of YAG:Nd laser radiation which is inefficient and technically difficult from the point of view of power.

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